## INTEGRATED CIRCUITS



Octal buffers (3-State)

Product specification

1994 Dec 05

IC15 Data Handbook

# **Philips Semiconductors**





### 74F244/74F244B

#### **FEATURES**

- Octal bus interface
- 3-State output buffer sink 64mA
- 15mA source current
- Guaranteed output skew less than 2.0ns (74F244B)
- Reduced ground bounce (74F244B)
- Reduced I<sub>CC</sub> (74F244B)
- Reduced loading (74F244B  $I_{IL} = 40\mu A$ )
- Split lead frame offers increased noise immunity (74F244B)
- Industrial temperature range available (-40°C to +85°C) for 74F244
- 74F244 available in SSOP Type II package

#### **ORDERING INFORMATION**

#### DESCRIPTION

The 74F244 is an octal buffer that is ideal for driving bus lines of buffer memory address registers. The outputs are all capable of sinking 64mA and sourcing up to 15mA, producing very good capacitive drive characteristics. The device features two output enables,  $\overline{OE}a$  and  $\overline{OE}b$ , each controlling four of the 3-State outputs.

The 74F244B is functionally equivalent to the 74F244. It has been designed to reduce effects of ground noise. Other advantages are noted in the features.

ТҮРЕ	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)		
74F244	4.0ns	53mA		
74F244B	4.0ns	33mA		

	ORDER	CODE		
	COMMERCIAL RANGE	INDUSTRIAL RANGE	PKG DWG #	
DESCRIPTION	$V_{CC}$ = 5V $\pm$ 10%,	$V_{CC}$ = 5V ±10%,	FRG DWG #	
	$T_{amb} = 0^{\circ}C \text{ to } +70^{\circ}C$	$T_{amb}$ = -40°C to +85°C		
20-pin plastic DIP	N74F244N, N74F244BN	I74F244N	SOT146-1	
20-pin plastic SOL	N74F244D, N74F244BD	I74F244D	SOT163-1	
20-pin plastic SSOP II	N74F244DB		SOT339-1	

### INPUT AND OUTPUT LOADING AND FAN OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
lan, Ibn	Data inputs (74F244)	1.0/2.67	20µA/1.6mA
	Data inputs (74F244B)	1.0/0.067	20μΑ/40μΑ
OEa, OEb	Output enable inputs (active low) (74F244)	1.0/1.67	20µA/1.0mA
	Output enable inputs (active low) (74F244B)	1.0/0.067	20μΑ/40μΑ
Yan, Ybn	Data outputs	750/106.7	15mA/64mA

**NOTE:** One (1.0) FAST unit load is defined as: 20µA in the high state and 0.6mA in the low state.

### **PIN CONFIGURATION**

OEa 1	20 VCC
la0 2	19 OEb
Yb0 3	18 Ya0
la1 4	17 lb0
Yb1 5	16 Ya1
la2 6	15 lb1
Yb2 7	14 Ya2
la3 8	13 lb2
Yb3 9	12 <sub>Ya3</sub>
GND 10	11 lb3
	0500207
	 SF00227

### LOGIC SYMBOL



## 74F244/74F244B

#### **IEC/IEEE SYMBOL**



### LOGIC DIAGRAM



### **FUNCTION TABLE**

	INP	OUTPUTS			
OEa	la	OEb	Ya	Yb	
L	L	L	L	L	L
L	Н	L	Н	Н	Н
н	Х	Н	Х	Z	Z

NOTES:

H = High voltage level

L = Low voltage level

X = Don't care Z = High impedance "off" state

### 74F244/74F244B

#### **ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V <sub>CC</sub>	Supply voltage		-0.5 to +7.0	V
V <sub>IN</sub>	Input voltage		-0.5 to +7.0	V
I <sub>IN</sub>	Input current		-30 to +5	mA
V <sub>OUT</sub>	Voltage applied to output in high output state		-0.5 to V <sub>CC</sub>	V
I <sub>OUT</sub>	Current applied to output in low output state		128	mA
		Commercial range	0 to +70	°C
T <sub>amb</sub>	Operating free air temperature range	Industrial range (74F244 only)	-40 to +85	°C
T <sub>stg</sub>	Storage temperature range	•	-65 to +150	°C

### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER			UNIT		
STWBOL	FARAMETER		MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage		4.5	5.0	5.5	V
V <sub>IN</sub>	High-level input voltage		2.0			V
V <sub>IL</sub>	Low-level input voltage			0.8	V	
I <sub>IK</sub>	Input clamp current			-18	mA	
I <sub>OH</sub>	High-level output current				-15	mA
i <sub>ol</sub>	Low-level output current				64	mA
		Commercial range	0		+70	°C
T <sub>amb</sub>	Operating free air temperature range	Industrial range (74F244 only)	-40		+85	°C

### 74F244/74F244B

### DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

CVMDO!	DADAME		TEST		LIMITS					
SYMBOL	PARAME	IER		C	CONDITIONS <sup>1</sup>		MIN	TYP <sup>2</sup>	MAX	IAX
				V <sub>CC</sub> = MIN,	I <sub>OH</sub> = -3mA	$\pm 10\% V_{CC}$	2.5			V
V <sub>OH</sub>	High-level output voltage			V <sub>IL</sub> = MAX,	V <sub>IL</sub> = MAX,			3.4		V
				V <sub>IH</sub> = MIN	I <sub>OH</sub> = -15mA	±10%V <sub>CC</sub>	2.0			V
					±5%V <sub>CC</sub>	2.0			V	
V <sub>OL</sub>	Low-level output voltage			$V_{CC} = MIN,$ $V_{IL} = MAX,$	I <sub>OL</sub> = MAX	±10%V <sub>CC</sub>			0.55	V
				V <sub>IH</sub> = MIN,	$V_{\rm IH} = MIN,$ $\pm 5\% V_{\rm C}$			0.42	0.55	V
V <sub>IK</sub>	Input clamp voltage			$V_{CC} = MIN, I_I =$		-0.73	-1.2	V		
l <sub>l</sub>	Input current at maximum inp	out voltage		$V_{CC} = MAX, V_I$	= 7.0V				100	μA
I <sub>IH</sub>	High-level input current			$V_{CC} = MAX, V_{I}$	= 2.7V				20	μA
		74F244 OEa, OEb							-1.0	mA
I <sub>IL</sub>	Low-level input current	74F244 Ian, Ibn		$V_{CC} = MAX, V_I = 0.5V$					-1.6	mA
		74F244B al	l inputs						-40	μA
I <sub>OZH</sub>	Off-state output current, high-level voltage applied			V <sub>CC</sub> = MAX, V <sub>O</sub> = 2.7V					50	μA
I <sub>OZL</sub>	Off-state output current, low-level voltage applied			V <sub>CC</sub> = MAX, V <sub>C</sub>	) = 0.5V				-50	μA
I <sub>OS</sub>	Short-circuit output current <sup>3</sup>			$V_{CC} = MAX$			-100		-225	mA
			I <sub>CCH</sub>					40	60	mA
		74F244	I <sub>CCL</sub>	$V_{CC} = MAX$				60	90	mA
I <sub>CC</sub>	Supply current (total)		I <sub>CCZ</sub>					60	90	mA
			I <sub>CCH</sub>					20	30	mA
		74F244B	I <sub>CCL</sub>	$V_{CC} = MAX$				50	70	mA
			I <sub>CCZ</sub>	]				29	40	mA

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

2. All typical values are at  $V_{CC} = 5V$ ,  $T_{amb} = 25^{\circ}C$ .

Not more than one output should be shorted at a time. For testing I<sub>OS</sub>, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.

### 74F244/74F244B

### **AC ELECTRICAL CHARACTERISTICS FOR 74F244**

						A POR	T LIMITS			
			TEST V <sub>CC</sub> = +5.0V			$T_{amb} = 0^{\circ}C$	C to +70°C	$T_{amb} = -40^{\circ}$	C to +85 $^{\circ}$ C	
SYMBOL	PARAMETER	TEST CONDITION				$\label{eq:V_CC} \begin{array}{l} \textbf{V}_{\text{CC}} = \textbf{+5.0V} \pm \textbf{10\%} \\ \textbf{C}_{\text{L}} = \textbf{50pF}, \\ \textbf{R}_{\text{L}} = \textbf{500}\Omega \end{array}$		$V_{CC}$ = +5.0V $\pm$ 10% $C_L$ = 50pF, $R_L$ = 500 $\Omega$		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay Ian, Ibn to Yn	Waveform 1	2.5 2.5	4.0 4.0	5.2 5.2	2.0 2.0	6.2 6.5	1.5 2.0	7.0 7.0	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output enable time to high or low	Waveform 2 Waveform 4	2.0 2.0	4.3 5.0	5.7 7.0	2.0 2.0	6.7 8.0	2.0 2.0	8.0 8.5	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output disable time from high or low	Waveform 2 Waveform 4	1.5 1.5	2.5 2.5	5.5 5.5	1.0 1.0	6.0 5.5	1.0 1.0	6.0 5.5	ns

### **AC ELECTRICAL CHARACTERISTICS FOR 74F244B**

					LIN	IITS		
SYMBOL	PARAMETER	TEST CONDITION	V	<sub>mb</sub> = +25 <sub>CC</sub> = +5.0 DpF,  R <sub>L</sub> :	V	T <sub>amb</sub> = 0°C V <sub>CC</sub> = +5. C <sub>L</sub> = 50pF,	UNIT	
			MIN	TYP	MAX	MIN	MAX	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay Ian, Ibn to Yn	Waveform 1	2.5 2.5	4.5 4.5	5.7 6.0	2.0 2.5	6.2 6.5	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output enable time to high or low level	Waveform 2 Waveform 4	2.0 3.0	4.0 5.5	6.0 7.5	2.0 3.0	6.5 8.0	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output disable time from high or low level	Waveform 2 Waveform 4	1.5 1.5	2.5 2.5	5.5 5.5	1.0 1.0	6.0 5.5	ns
t <sub>sk(0)</sub>	Output skew <sup>1, 2</sup>	Waveform 3			1.5		2.0	ns

NOTES:

1.  $|t_{PN} \text{ actual} - t_{PM} \text{ actual}|$  for any output compared to any other output where N and M are either LH or HL. 2. Skew times are valid only under same test conditions (temperature, V<sub>CC</sub>, loading, etc.,).

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## Octal buffers (3-State)

### 74F244/74F244B

### AC WAVEFORMS



Waveform 1. Propagation Delay for data to outputs



Waveform 2. 3-State output enable time to high level and output disable time from high level



Waveform 3. Output skew



Waveform 4. 3-State output enable time to low level and output disable time from low level



### **TEST CIRCUIT AND WAVEFORMS**

SOT146-1

### 74F244/74F244B





#### DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A <sub>1</sub> min.	A <sub>2</sub> max.	b	b <sub>1</sub>	с	D <sup>(1)</sup>	Е <sup>(1)</sup>	e	e <sub>1</sub>	L	M <sub>E</sub>	M <sub>H</sub>	w	Z <sup>(1)</sup> max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	0.36 0.23	26.92 26.54	6.40 6.22	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.0
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.014 0.009	1.060 1.045	0.25 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.078

#### Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFEF	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ	PROJECTION	1550E DATE	
SOT146-1			SC603		<del>-92-11-17</del> 95-05-24	

### 74F244/74F244B



#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT163-1	075E04	MS-013AC				<del>-92-11-17</del> 95-01-24

### 74F244/74F244B



## 74F244/74F244B

NOTES

### 74F244/74F244B

DEFINITIONS					
Data Sheet Identification	Product Status	Definition			
Objective Specification	Formative or in Design	This data sheet contains the design target or goal specifications for product development. Specifications may change in any manner without notice.	9397-750-05103		
Preliminary Specification Preproduction Product		This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.			
Product Specification	Full Production	This data sheet contains Final Specifications. Philips Semiconductors reserves the right to make changes at any time without notice, in order to improve design and supply the best possible product.			

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(print code)

Date of release: October 28, 1991

Document order number:

9397-750-05103